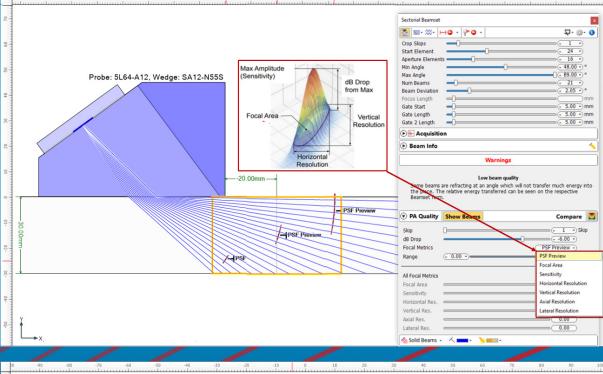
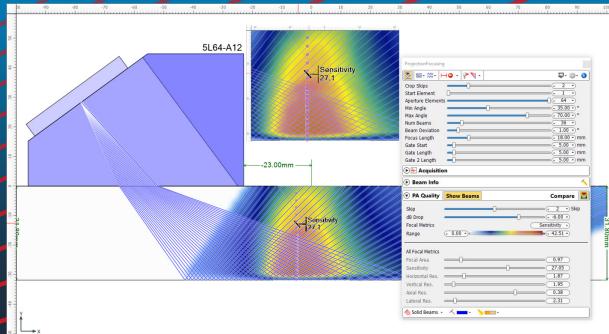


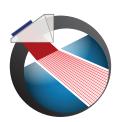
- **ECLIPSE**
- Sensitivity map helps assess sensitivity to flaws / difficulty of performing calibration
- Vertical Resolution map facilitates estimation of sizing accuracy for given inspection
- Focal Area map provides means of comparing overall focusing of candidate techniques Support for FMC/TFM, Linear, Sectorial and Compound scans - True Depth, Half Path
- and Projection Focusing
- Available for standard and custom pieces





the new features here to see





## BEANTOOL 11



## Scan here to see all the new features in BeamTool 11

## **Compare Feature:**

- New split screen display allows easy comparison between techniques
- Can compare different probes, beamsets and focusing options
- Focal quality metric maps and PSF simulations can be viewed simultaneously
- Focal quality metric readouts help select optimal essential technique parameters

